





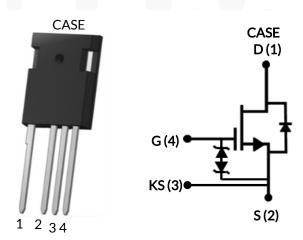








UJ4C075018K4S



Part Number	Package	Marking
UJ4C075018K4S	TO-247-4L	UJ4C075018K4S









750V-18m Ω SiC FET

Rev. A, October 2020

Description

The UJ4C075018K4S is a 750V, $18m\Omega$ G4 SiC FET. It is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the TO-247-4L package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- On-resistance $R_{DS(on)}$: $18m\Omega$ (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 102nC
- ◆ Low body diode V_{FSD}: 1.14V
- ◆ Low gate charge: Q_G = 37.8nC
- Threshold voltage V_{G(th)}: 4.8V (typ) allowing 0 to 15V drive
- Low intrinsic capacitance
- ESD protected, HBM class 2
- TO-247-4L package for faster switching, clean gate waveforms

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		750	V
Gate-source voltage	V_{GS}	DC	-20 to +20	V
Continuous dusis summent 1	I _D	T _C = 25°C	81	Α
Continuous drain current ¹		T _C = 100°C	60	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	205	Α
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =3.6A	97.2	mJ
Power dissipation	P _{tot}	T _C = 25°C	385	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J,T_STG		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	T _L		250	°C

- 1. Limited by $T_{J,max}$
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.3	0.39	°C/W













Electrical Characteristics ($T_J = +25$ °C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Units		
	Symbol		Min	Тур	Max	Units
Drain-source breakdown voltage	BV _{DS}	$V_{GS}=0V, I_D=1mA$	750			V
Total drain leakage current		V _{DS} =750V, V _{GS} =0V, T _J =25°C		1.3	125	- μΑ
	I _{DSS}	V _{DS} =750V, V _{GS} =0V, T _J =175°C		20		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		4.7	±20	μА
Drain-source on-resistance	R _{DS(on)}	V_{GS} =12V, I_{D} =20A, T_{J} =25°C		18	23	
		V _{GS} =12V, I _D =20A, T _J =125°C		31		mΩ
		V _{GS} =12V, I _D =20A, T _J =175°C		41		
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_D =10mA	4	4.8	6	V
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C =25°C			81	Α
Diode pulse current ²	$I_{S,pulse}$	T _C =25°C			205	Α
Forward voltage	V_{FSD}	V _{GS} =0V, I _F =20A, T _J =25°C		1.14	1.46	. V
		V _{GS} =0V, I _F =20A, T _J =175°C		1.35		
Reverse recovery charge	Q_{rr}	V_{DS} =400V, I_{S} =50A, V_{GS} =-0V, R_{G_EXT} =50 Ω		102		nC
Reverse recovery time	t _{rr}	di/dt=1300A/μs, Τ _J =25°C		25		ns
Reverse recovery charge	Q _{rr}	V_{DS} =400V, I_{S} =50A, V_{GS} =-0V, R_{G_EXT} =50 Ω		109		nC
Reverse recovery time	t _{rr}	di/dt=1300A/μs, Τ _J =150°C		27		ns













Typical Performance - Dynamic

Parameter	Symbol	Took Conditions	Value			Units
	Symbol	Test Conditions	Min	Тур	Max	Offics
Input capacitance	C _{iss}	V _{DS} =100V, V _{GS} =0V		1422		
Output capacitance	C _{oss}	f=100kHz		217		pF
Reverse transfer capacitance	C_{rss}	1-100KHZ		2		
Effective output capacitance, energy related	C _{oss(er)}	V_{DS} =0V to 400V, V_{GS} =0V		150		pF
Effective output capacitance, time related	C _{oss(tr)}	V_{DS} =0V to 400V, V_{GS} =0V		280		pF
C _{OSS} stored energy	E _{oss}	V_{DS} =400V, V_{GS} =0V		12		μЈ
Total gate charge	Q_G	V _{DS} =400V, I _D =50A,		37.8		
Gate-drain charge	Q_{GD}	$V_{DS} = 400 \text{ V}, I_D = 50 \text{ A},$ $V_{GS} = 0 \text{ V} \text{ to } 15 \text{ V}$		8		nC
Gate-source charge	Q_{GS}	V _{GS} – 0V t013V		11.8		1
Turn-on delay time	t _{d(on)}	Note 4,		13		
Rise time	t _r	V _{DS} =400V, I _D =50A,		35		
Turn-off delay time	t _{d(off)}	Gate Driver = $0V \text{ to } +15V$, Turn-on $R_{G,EXT} = 1\Omega$,		146		ns
Fall time	t _f	Turn-off $R_{G,EXT}$ =50 Ω		17		
Turn-on energy	E _{ON}	Inductive Load, FWD: same device with		407		
Turn-off energy	E _{OFF}	$V_{GS} = 0V, R_G = 50\Omega,$		255		μJ
Total switching energy	E _{TOTAL}	T _J =25°C		662		
Turn-on delay time	t _{d(on)}	Note 4,		13		
Rise time	t _r	V _{DS} =400V, I _D =50A,		39		nc
Turn-off delay time	t _{d(off)}	$\begin{array}{c c} \text{Gate Driver = 0V to +15V,} \\ \text{Turn-on R}_{\text{G,EXT}} = 1\Omega, \\ \text{Turn-off R}_{\text{G,EXT}} = 50\Omega \end{array}$		151		ns
Fall time	t _f			21		
Turn-on energy	E _{ON}	Inductive Load, FWD: same device with		453		
Turn-off energy	E _{OFF}	$V_{GS} = 0V, R_G = 50\Omega,$		304		μЈ
Total switching energy	E _{TOTAL}	T _J =150°C		757		

^{4.} Measured with the half-bridge mode switching test circuit in Figure 28.













Typical Performance - Dynamic (continued)

Parameter	Cymphol	Test Conditions	Value			Units
Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Turn-on delay time	t _{d(on)}	Note 5,		13		
Rise time	t _r			39		ns
Turn-off delay time	$t_{d(off)}$	V _{DS} =400V, I _D =50A, Gate Driver =0V to +15V,		30		- ns
Fall time	t _f	$R_{G,EXT}=1\Omega$, inductive Load,		9		
Turn-on energy including R _S energy	E _{ON}	FWD: same device with V_{GS}		418		
Turn-off energy including R_S energy	E _{OFF}	= 0V and $R_G = 1\Omega$, RC snubber: $R_{S1} = 10\Omega$ and		55		
Total switching energy	E _{TOTAL}	C _{S1} =300pF,		473		μЈ
Snubber R _S energy during turn-on	E _{RS_ON}	T _J =25°C		3.5		
Snubber R _S energy during turn-off	E _{RS_OFF}			6		
Turn-on delay time	t _{d(on)}			13		
Rise time	t _r	Note 5,		44		
Turn-off delay time	t _{d(off)}	V _{DS} =400V, I _D =50A, Gate Driver =0V to +15V,		35		ns
Fall time	t _f	$R_{G,EXT}=1\Omega$, inductive Load,		9		
Turn-on energy including R _S energy	E _{ON}	FWD: same device with V _{GS}		467		
Turn-off energy including R _S energy	E _{OFF}	= 0V and $R_G = 1\Omega$, RC snubber: R_{S1} =10 Ω and C_{S1} =300pF, T_J =150°C		58		
Total switching energy	E _{TOTAL}			525		μЈ
Snubber R _S energy during turn-on	E _{RS_ON}			3.5		
Snubber R _S energy during turn-off	E _{RS_OFF}			6		
Turn-on delay time	t _{d(on)}	Note 6,		13		
Rise time	t _r	V _{DS} =400V, I _D =50A, Gate		34]
Turn-off delay time	t _{d(off)}	Driver =0V to +15V,		146		ns
Fall time	t _f	Turn-on $R_{G,EXT} = 1\Omega$,		18		
Turn-on energy	E _{ON}	Turn-off $R_{G,EXT}$ =50 Ω Inductive Load,		360		
Turn-off energy	E _{OFF}	FWD: UJ3D06530TS		268		μͿ
Total switching energy	E _{TOTAL}	T _J =25°C		628		-
Turn-on delay time	t _{d(on)}	Note 6,		13		
Rise time	t _r	V _{DS} =400V, I _D =50A, Gate		38		
Turn-off delay time	t _{d(off)}	Driver =0V to +15V, Turn-on $R_{G,EXT}$ =1 Ω ,		152		ns
Fall time	t _f			19		1
Turn-on energy	E _{ON}	Turn-off $R_{G,EXT}$ =50Ω – Inductive Load,		410		
Turn-off energy	E _{OFF}	FWD: UJ3D06530TS T _J =150°C		305		- μJ
Total switching energy	E _{TOTAL}			715		

- 5. Measured with the chopper mode switching test circuit in Figure 30.
- 6. Measured with the chopper mode switching test circuit in Figure 29.





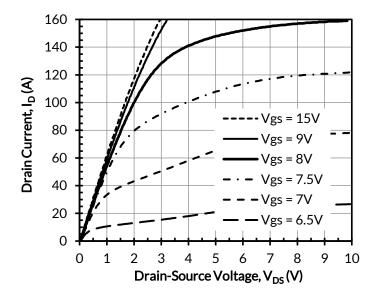








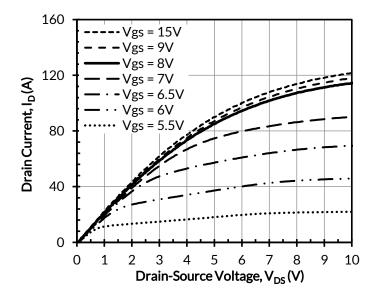
Typical Performance Diagrams



160 120 Drain Current, I_D (A) - Vgs = 15V Vgs = 9V 80 Vgs = 8VVgs = 7V- Vgs = 6.5V 40 Vgs = 6V 0 0 1 2 3 5 10 Drain-Source Voltage, V_{DS} (V)

Figure 1. Typical output characteristics at T_J = - 55°C, tp < 250 μ s

Figure 2. Typical output characteristics at $T_J = 25$ °C, $tp < 250\mu s$



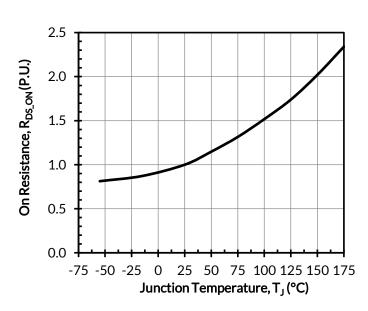


Figure 3. Typical output characteristics at T_J = 175°C, tp < 250 μ s

Figure 4. Normalized on-resistance vs. temperature at $V_{GS} = 12V$ and $I_D = 50A$



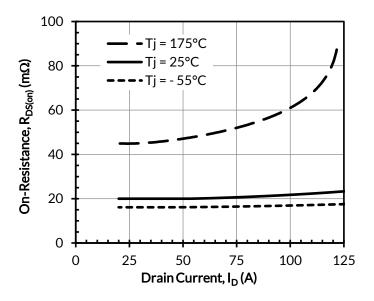












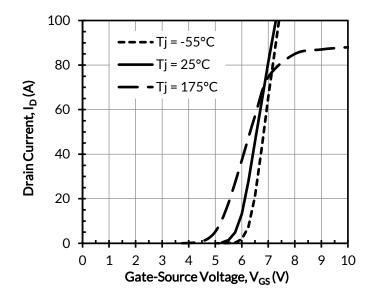
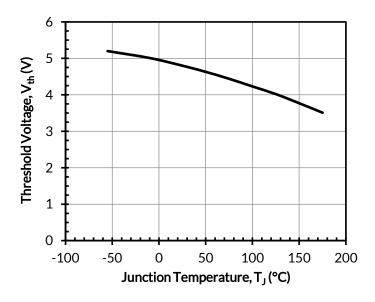


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at $V_{DS} = 5V$



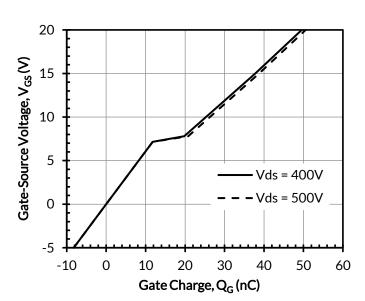


Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_{D} = 10mA

Figure 8. Typical gate charge at I_D = 50A



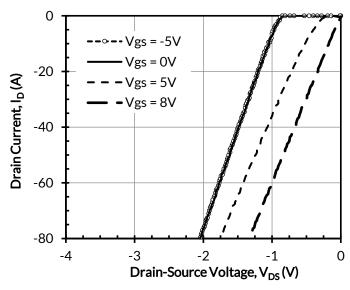














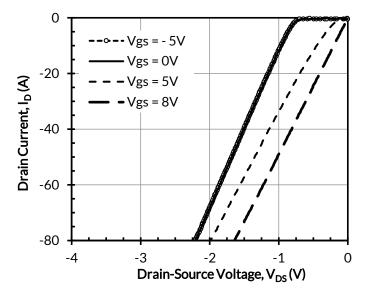


Figure 10. 3rd quadrant characteristics at T_J = 25°C

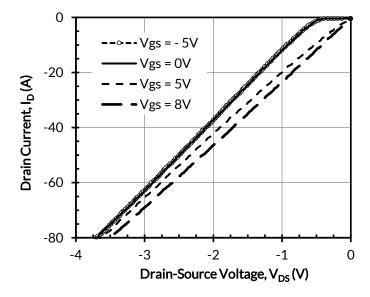


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

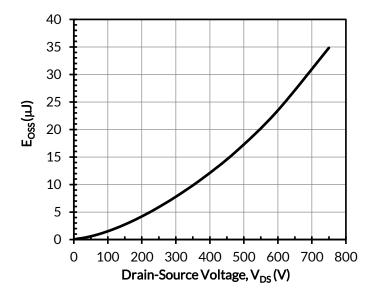


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$



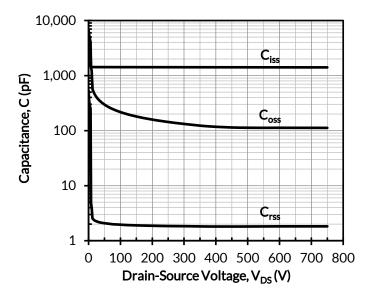








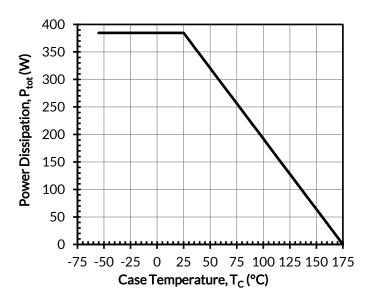




100 80 40 -75 -50 -25 0 25 50 75 100 125 150 175 Case Temperature, T_C (°C)

Figure 13. Typical capacitances at f = 100kHz and $V_{GS} = 0V$

Figure 14. DC drain current derating



1 Thermal Impedance, $Z_{\theta JC}$ (°C/W) 0.1 D = 0.5D = 0.3D = 0.1 0.01 • D = 0.05 ···· D = 0.02 -D = 0.01Single Pulse 0.001 1.E-06 1.E-05 1.E-04 1.E-03 1.E-02 1.E-01 Pulse Time, t_p (s)

Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance













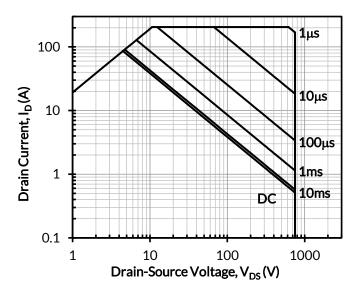


Figure 17. Safe operation area at $T_C = 25$ °C, D = 0, Parameter t_p

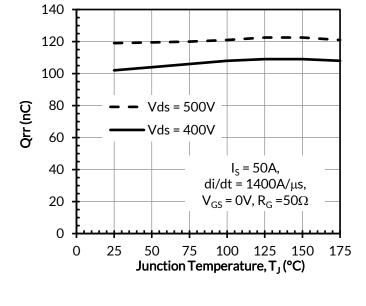


Figure 18. Reverse recovery charge Qrr vs. junction temperature

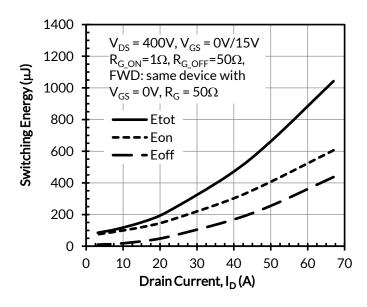


Figure 19. Clamped inductive switching energy vs. drain current at V_{DS} = 400V and T_J = 25°C

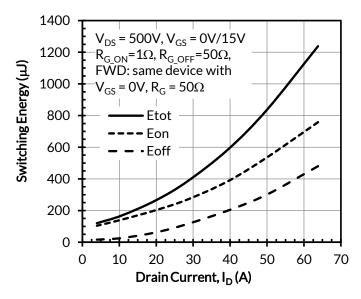


Figure 20. Clamped inductive switching energy vs. drain current at V_{DS} = 500V and T_J = 25°C



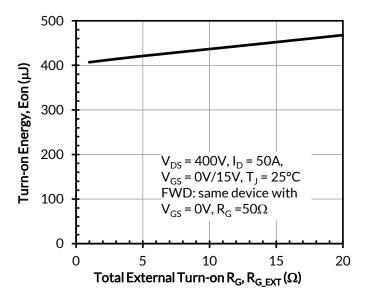








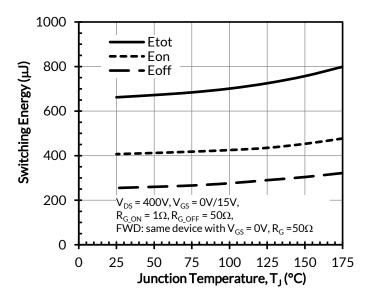




500 400 Turn-Off Energy, Eoff (μJ) 300 200 $V_{DS} = 400V, I_{D} = 50A,$ $V_{GS} = 0V/15V, T_{J} = 25^{\circ}C$ 100 FWD: same device with $V_{GS} = 0V, R_G = 50\Omega$ 0 0 20 40 60 80 100 Total External Turn-off R_G , $R_{G,EXT}(\Omega)$

Figure 21. Clamped inductive switching turn-on energy vs. R_{G,EXT_ON}

Figure 22. Clamped inductive switching turn-off energy vs. $R_{\text{G,EXT_OFF}}$



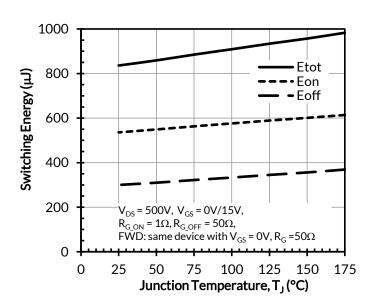


Figure 23. Clamped inductive switching energy vs. junction temperature at V_{DS} =400V and I_{D} = 50A

Figure 24. Clamped inductive switching energy vs. junction temperature at V_{DS} = 500V and I_D = 50A



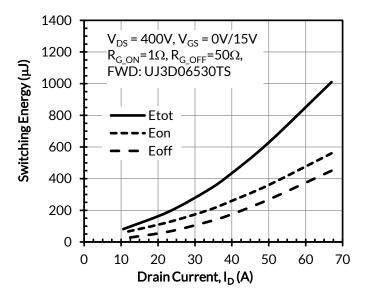








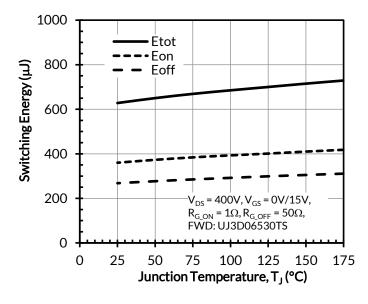




1400 $V_{DS} = 500V, V_{GS} = 0V/15V$ 1200 R_{G_ON} =1 Ω , R_{G_OFF} =50 Ω , FWD: UJ3D06530TS Switching Energy (µJ) 1000 800 **Etot** Eon 600 **Eoff** 400 200 0 40 50 60 70 10 30 Drain Current, I_D (A)

Figure 24. Clamped inductive switching energy vs. drain current at V_{DS} = 400V and T_J = 25°C

Figure 25. Clamped inductive switching energy vs. drain current at V_{DS} = 500V and T_J = 25°C



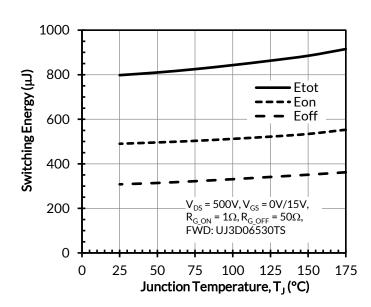


Figure 26. Clamped inductive switching energy vs. junction temperature at V_{DS} =400V and I_{D} = 50A

Figure 27. Clamped inductive switching energy vs. junction temperature at V_{DS} = 500V and I_D = 50A













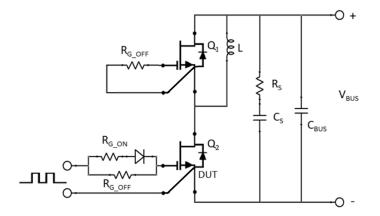


Figure 28. Schematic of the half-bridge mode switching test circuit. Note, a bus RC snubber (R_S = 2.5Ω , C_S =100nF) is used to reduce the power loop high frequency oscillations.

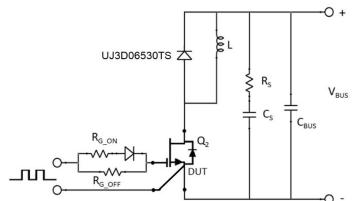


Figure 29. Schematic of the chopper mode switching test circuit. Note, a bus RC snubber (R_S = 2.5 Ω , C_S =100nF) is used to reduce the power loop high frequency oscillations.

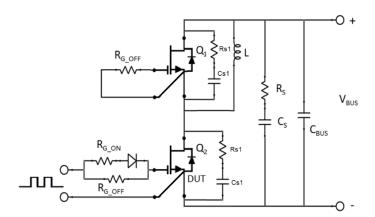


Figure 30. Schematic of the half-bridge mode switching test circuit with device RC snubbers (R_{s1} = 10Ω , C_{s1} = 300pF) and a bus RC snubber (R_{S} = 2.5Ω , C_{S} =100nF).













Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at www.unitedsic.com

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